



## N-Channel Enhancement Mode Field Effect Transistor

### Product Summary

$V_{DS}$	30V
$I_D$	50A
$R_{DS(ON)}$ ( at $V_{GS}= 10V$ )	7.3mohm
$R_{DS(ON)}$ ( at $V_{GS}= 4.5V$ )	11.5mohm
100% EAS Tested	
100% $V_{DS}$ Tested	

### General Description

Excellent package for heat dissipation  
High density cell design for low  $R_{DS(ON)}$



# YJD50N03A

## Electrical Characteristics ( $T_J=25$ unless otherwise noted)

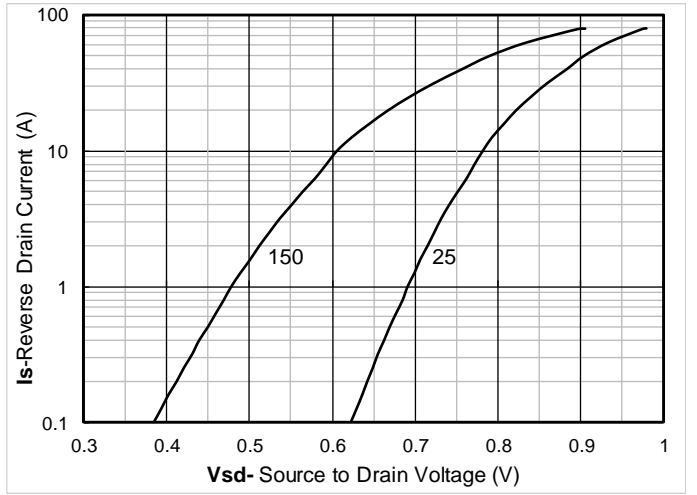
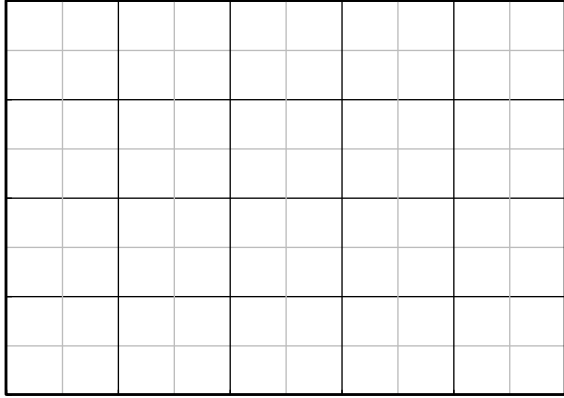
Parameter	Symbol	Conditions	Min	Typ	Max	Units
<b>Static Parameter</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS}=0V, I_D=250$	30			V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=30V, V_{GS}=0V$			1	
		$V_{DS}=30V, V_{GS}=0V, T_J=150$			100	
Gate-Body Leakage Current	$I_{GSS}$	$V_{GS}=20V, V_{DS}=0V$			100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250$	1.0	1.5	2.2	V
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=15A$		5.4	7.3	m
		$V_{GS}=4.5V, I_D=15A$		9.5	11.5	
Diode Forward Voltage	$V_{SD}$	$I_S=15A, V_{GS}=0V$		0.85	1.2	V
Maximum Body-Diode Continuous Current	$I_S$				50	A
Gate resistance	$R_G$	$f=1MHz$		4		
<b>Dynamic Parameters</b>						
Input Capacitance	$C_{iss}$	$V_{DS}=15V, V_{GS}=0V, f=1MHz$		1015		pF
Output Capacitance	$C_{oss}$			201		
Reverse Transfer Capacitance	$C_{rss}$			164		
<b>Switching Parameters</b>						
Total Gate Charge	$Q_g$	$V_{GS}=10V, V_{DS}=20V, I_D=20A$		23.6		nC
Gate-Source Charge	$Q_{gs}$			3.9		
Gate-Drain Charge	$Q_{gd}$			7		
Reverse Recovery Charge	$Q_{rr}$	$I_r=20A, di/dt=100A/us$		0.2		
Reverse Recovery Time	$t_{rr}$			5		
Turn-on Delay Time	$t_{D(on)}$					ns







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Figure

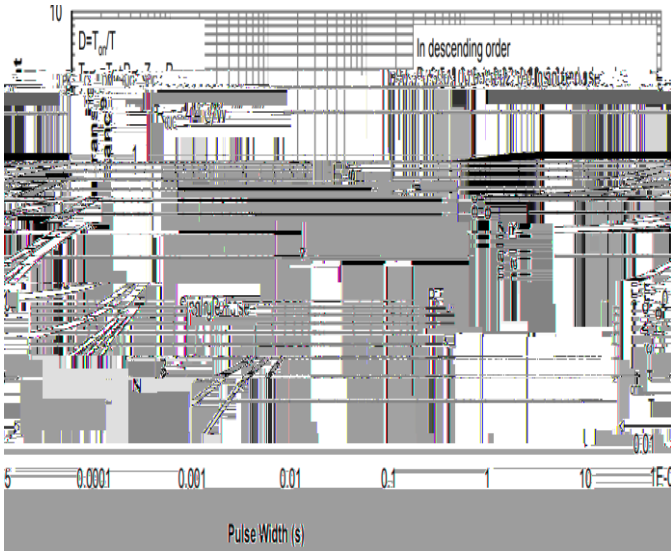


Figure 13. Normalized Maximum Transient Thermal Impedance

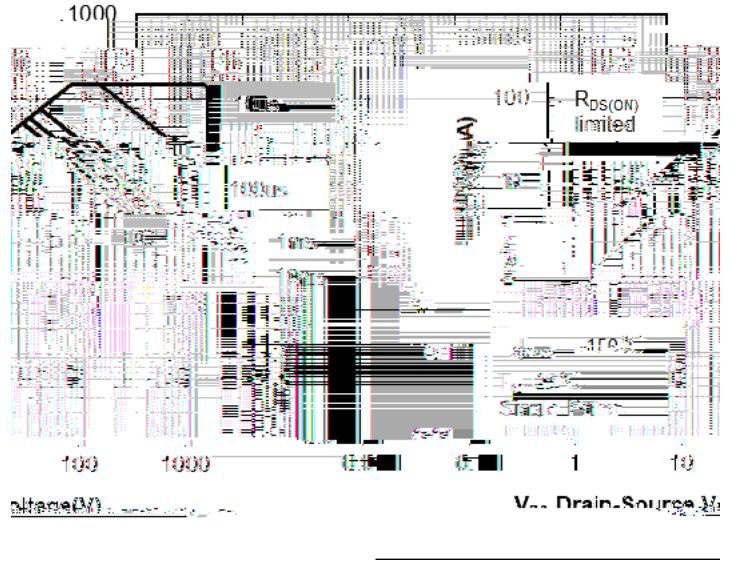
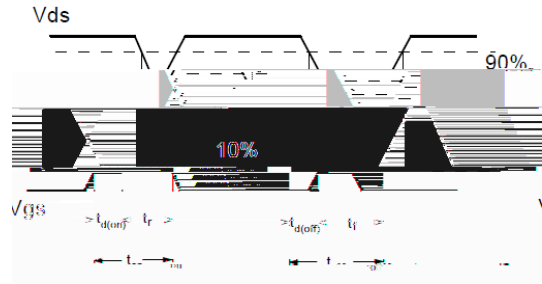
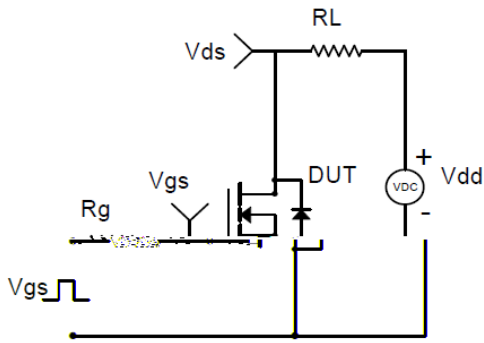
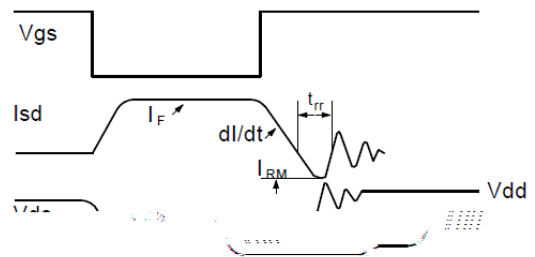
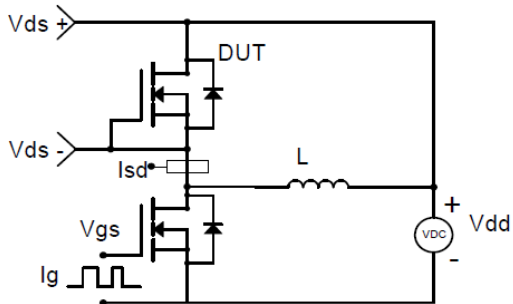


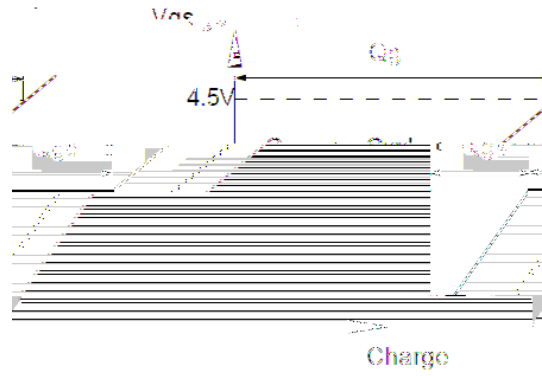
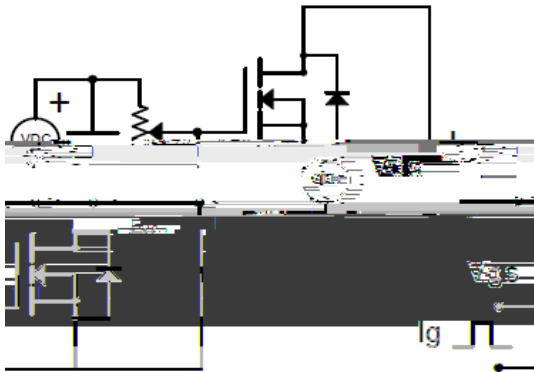
Figure 14. Safe Operation Area



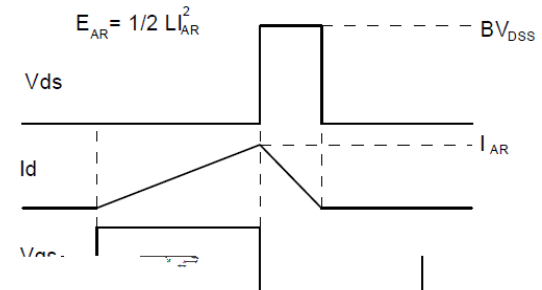
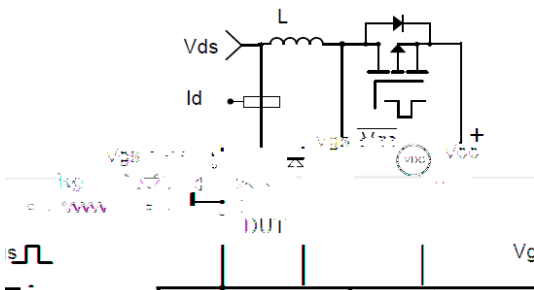
**Resistive Switching Test Circuit & Waveforms**



**Diode Recovery Test Circuit & Waveforms**



**Gate Charge Test Circuit & Waveform**



**Unclamped Inductive Switching (UIS) Test Circuit & Waveforms**

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